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Supporting information for article:

Multielectrode electrochemical cell for *in-situ* structural characterization of amorphous thin film catalysts using high-energy X-ray scattering

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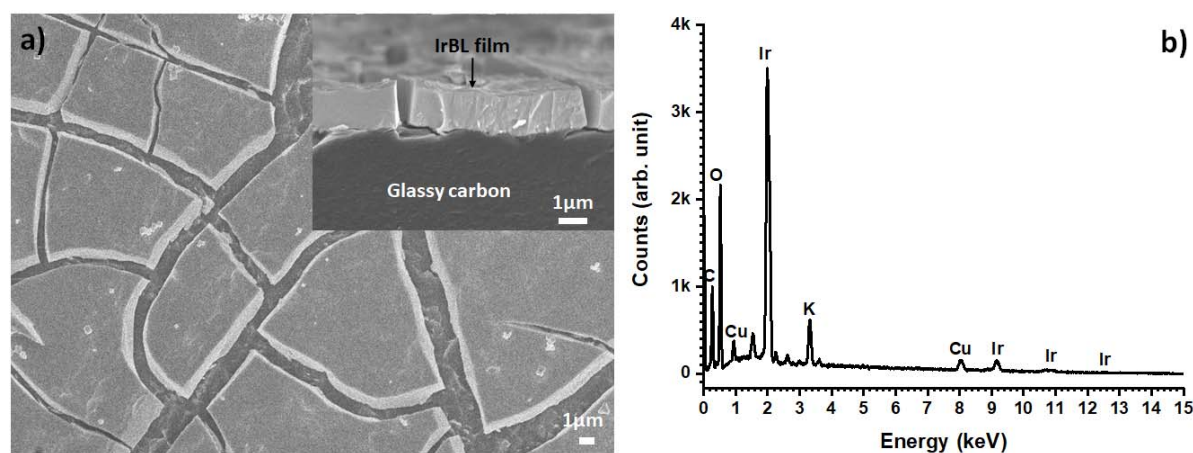


Figure S1. a) SEM images and b) EDX data of an IrBL film on a GC electrode. Copper (Cu) in the EDX spectrum originated from the copper tape providing electrical contact between the IrBL film on GC and the sample holder. EDX data were acquired at 15 kV of acceleration voltage and 10000x magnification. The deposition time of the IrBL film in the E-cell was 150 min. Cracking of the film originates from dehydration due to the vacuum condition for obtaining the SEM image or drying under ambient conditions.

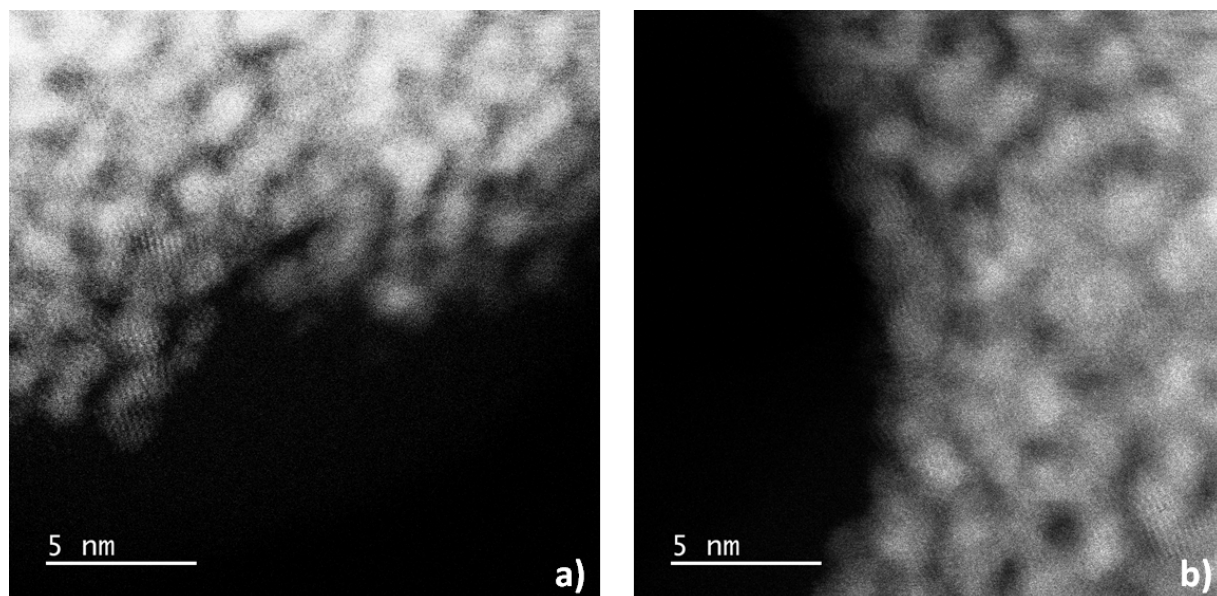


Figure S2. HAADF-STEM images of IrBL powder after the in situ experiment shown in **Figure 7. a)** and **b)** were obtained at room temperature and at LN₂ temperature, respectively. Crystallization and agglomeration occurred immediately with electron beam exposure.